

Application/Control No.	Applicant(s)/Patent u Reexamination	nder	
10/805,204	ADEGAWA, YUTAK	ADEGAWA, YUTAKA	
Examiner	Art Unit		
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
OB	3/8/5	W
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